

# VLSI Chip Design Project TSEK06

## Project description and requirement specification

Version 1.0

**Project: Low Power 8-Bit Successive  
Approximation Analog-to-Digital Converter**

**Project number: 8**

### Project Group:

Name	Project members	Telephone	E-mail
	Project leader and designer 1(5)		
	Designer 2(5)		
	Designer 3(5)		
	Designer 4(5)		
	Designer 5(5)		

**Customer and supervisor:** Dai Zhang

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# 1 Background

This document describes the design requirement specification of an 8-bit low power successive approximation (SA) analog-to-digital converter (ADC). Low power ADCs are highly demanded in battery-powered or portable communication devices. Among different types of ADCs, the SA ADC has the advantage of low power dissipation at medium speed and medium resolution due to its simple architecture with only one comparator in the whole system.

## 1.1 Project goal

The project goal is to design an integrated circuit (IC) in complementary metal-oxide semiconductor (CMOS) technology. Students, participating in this project as project members and project leaders, should learn the different steps of the IC design flow. That includes the given system architecture analysis, simulation, layout implementation and verification. The project students have an optional choice to manufacture the designed IC circuit on a chip. To test the manufactured chips, another course (TSEK11) is available after the project.

## 1.2 Milestones and deadline

1: Project selection	Week 3
2: Pre-study, project planning, and discussion with supervisor	Week 4
3: High-level modeling design and simulation result (report)	February 12
4: Gate/transistor level design and simulations result (report)	March 5
5: Layout, DRC, parasitic extraction, LVS, post-layout simulations, modification and chip evaluations.	April 30
6: <b>DEADLINE</b> , Delivery of the completed chip.	<b>May 7</b>
7: <b>DEADLINE</b> , Final report, and oral presentation	<b>May 21</b>

## 1.3 Parties

The following parties are involved in this project:

- 1- Customer: Dai Zhang
- 2- Project supervisor: Dai Zhang

Tasks:

- Formulates the project requirements.
- Provides technical support.
- Reviews the project documents.

- 3- Project leader: One of the members in the design team.

Tasks:

- Responsible for organization of the team and the project planning.
- Divides the design and documentation work in an efficient way
- Organizes the team meetings as well as the meetings between the team and supervisor

- Keeps the supervisor informed about the progress of the project (**at least one email or meeting per week**)
- 4- Project design members (including the project leader)
- Are equally responsible for project planning and design.
  - Participate actively in all the meetings.
  - Support the team and the project leader.
  - Keep the team and project leader informed about the progress of their tasks.

## 2 Project description

### 2.1 System description

The SA ADC, shown in Figure 1, consists of a comparator, a sample and hold (S/H) circuit, a digital-to-analog converter (DAC) and a successive approximation register (SAR). It is designed based on a binary search algorithm and a charge redistribution principle. Binary weighted capacitors are used for the DAC.

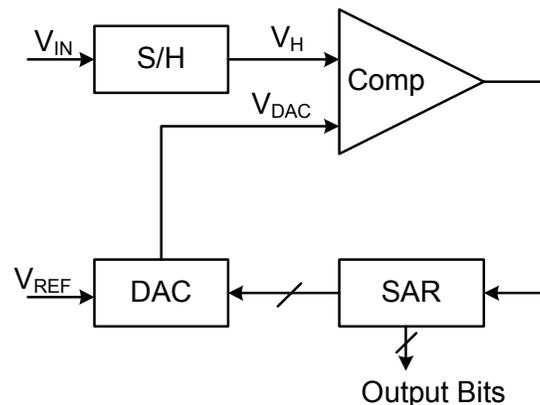


Figure 1: Block diagram of SA ADC

The timing diagram of an 8-bit SA ADC is shown in Figure 2. At the first clock cycle, the input voltage is sampled, and the SAR & DAC are reset. The conversion starts from the most-significant-bit (MSB) at the second clock cycle, by the comparison between  $V_H$  and  $V_{REF}/2$ . The decision from the comparator is then loaded by the SAR. At the next conversion cycle, the SAR outputs a digital word to the DAC, which contains both the previous decision and the current guess. As the clock cycles increase, the output of the DAC successively approximates the sampled voltage. One bit is obtained per clock cycle.

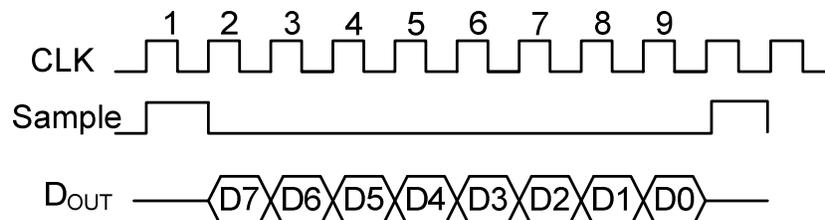


Figure 2: Timing diagram of 8-bit SA ADC

The SAR control logic is a sequential finite state machine, which generates the approximation sequence of 9 steps, given by Table 1. As explained above, step 0 is sampling step. For the generic step ( $s=1\dots 8$ ), three operations are performed: 1) it makes a guess '1'; 2) it loads the decision bit from the comparator; 3) it stores the determined bit which generated at  $s-1$  step.

Table 1: SAR algorithm for 8-bit ADC

Step	SAR								Sample	COMP
0	0	0	0	0	0	0	0	0	1	-
1	1	0	0	0	0	0	0	0	0	D7
2	D7	1	0	0	0	0	0	0	0	D6
3	D7	D6	1	0	0	0	0	0	0	D5
4	D7	D6	D5	1	0	0	0	0	0	D4
5	D7	D6	D5	D4	1	0	0	0	0	D3
6	D7	D6	D5	D4	D3	1	0	0	0	D2
7	D7	D6	D5	D4	D3	D2	1	0	0	D1
8	D7	D6	D5	D4	D3	D2	D1	1	0	D0

## 2.2 Important design metrics

The circuit should be designed for a sampling frequency of at least 100 KHz and it is aimed for low power application. Moreover, the performances of the circuit need to be evaluated, for example the signal-to-noise-and-distortion ratio (SNDR) of the ADC.

Important things to be considered are:

- Switch charge error during sampling
- Matching of the capacitive DAC
- Total power dissipation of the ADC

## 3 Area and performance requirements

Table 2 summarizes the circuit performance requirements. Each requirement has its number, formulated text, and the given degree of priority. Three degrees of priority are used: high, medium, and low. High is a firm requirement with no possibility of relaxation, while medium requirements can be relaxed somewhat after good motivation.

Table 2: Circuit performance requirements

Requirement	Requirement text	Priority
1	Sampling frequency at least 100KHz	High
2	Evaluate the performance of ADC	High
3	Low power optimization	High

<b>4</b>	Layout matching	High
<b>5</b>	Integrate as many system components as possible on-chip	High
<b>6</b>	Schematic and layout must be verified by simulation	High
<b>7</b>	Chip core area < 0.27mm <sup>2</sup>	High
<b>8</b>	Total project pin count: 12	High
<b>9</b>	Design technology is AMS 4-Metal 0.35µm CMOS	High
<b>10</b>	The most important system nodes should have off-chip access pins	Low
<b>11</b>	On-chip current densities < 1 mA/µm	High
<b>12</b>	All requirements fulfilled in “ <i>typical</i> ”, “ <i>slow</i> ”, and “ <i>fast</i> ” process corners and for temperatures between 25°C and 110°C	Medium

### **3.1 Available resources**

- Scientific publication database (available from LiU):
- IEL – IEEE/IEE Electronic Library, <http://www.bibl.liu.se/english/databas/>

### **3.2 Tools**

- Circuit simulation and layout tools from Cadence<sup>®</sup>, <http://www.cadence.com/>

## **4 References**

- Maxim, “Understanding SAR ADCs”, Application Note 1080, Mar 01, 2001.
- K. H. Lundberg, “Analog-to-Digital Converter Testing,”  
<http://www.mit.edu/people/klund/A2Dtesting.pdf>, accessed: Dec. 2009.
- J.M. Rabaey, A. Chandrakasan, and B. Nikolic, Digital Integrated Circuits, 2nd ed., Prentice Hall, 2003, ISBN 0-13-120764-4.
- B. Razavi, Design of Analog CMOS Integrated Circuits, McGraw-Hill, 1st edition, 1999.

For more literature references consult with your supervisor.

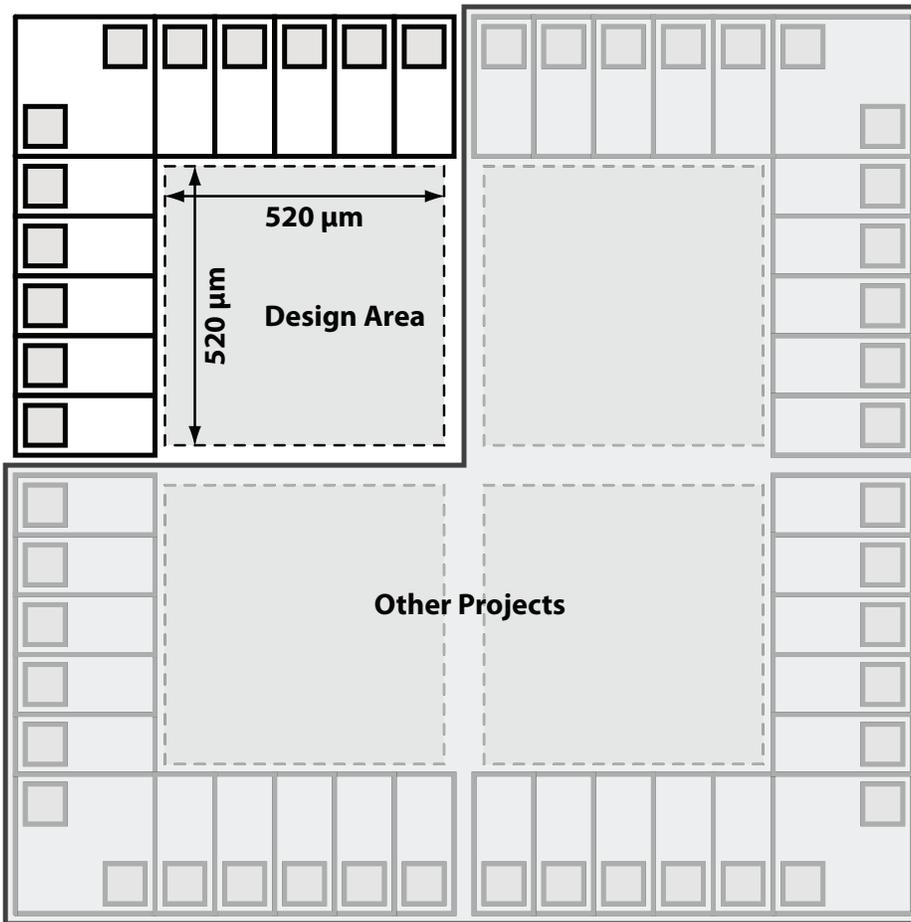


Figure 3: Schematic picture of a 3mm<sup>2</sup> chip highlighting one corner with 10 generic pads, one  $V_{DD}$  and one  $V_{SS}$  pad (total 12 per group). Four groups will then share one chip.